OCTOBER 1976 – REVISED MARCH 1988

- **Synchronous Load**
- **Direct Overriding Clear**
- **Parallel to Serial Conversion**

TYPE	TYPICAL MAXIMUM CLOCK FREQUENCY	TYPICAL POWER DISSIPATION
'166	35 MHz	360 mW
'LS166A	35 MHz	100 mW

description

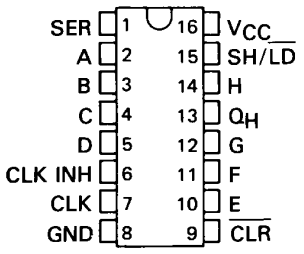
The '166 and 'LS166A 8-bit shift registers are compatible with most other TTL logic families. All '166 and 'LS166A inputs are buffered to lower the drive requirements to one Series 54/74 or Series 54LS/74LS standard load, respectively. Input clamping diodes minimize switching transients and simplify system design.

These parallel-in or serial-in, serial-out shift registers have a complexity of 77 equivalent gates on a monolithic chip. They feature gated clock inputs and an overriding clear input. The parallel-in or serial-in modes are established by the shift/load input. When high, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. When low, the parallel (broadside) data inputs are enabled and synchronous loading occurs on the next clock pulse. During parallel loading, serial data flow is inhibited. Clocking is accomplished on the low-to-high-level edge of the clock pulse through a two-input positive NOR gate permitting one input to be used as a clock-enable or clock-inhibit function. Holding either of the clock inputs high inhibits clocking; holding either low enables the other clock input. This, of course, allows the system clock to be free-running and the register can be stopped on command with the other clock input. The clock inhibit input should be changed to the high level only while the clock input is high. A buffered, direct clear input overrides all other inputs, including the clock, and sets all flip-flops to zero.

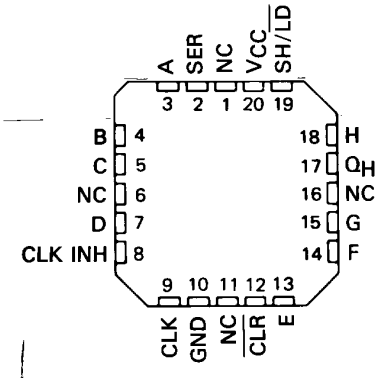
FUNCTION TABLE

INPUTS						INTERNAL OUTPUTS		OUTPUT
CLEAR	SHIFT/LOAD	CLOCK INHIBIT	CLOCK	SERIAL	PARALLEL A...H	Q_A	Q_B	Q_H
L	X	X	X	X	X	L	L	L
H	X	L	L	X	X	Q_{A0}	Q_{B0}	Q_{H0}
H	L	L	↑	X	a...h	a	b	h
H	H	L	↑	H	X	H	Q_{An}	Q_{Gn}
H	H	L	↑	L	X	L	Q_{An}	Q_{Gn}
H	X	H	↑	X	X	Q_{A0}	Q_{B0}	Q_{H0}

SN54166, SN54LS166A . . . J OR W PACKAGE
SN74166 . . . N PACKAGE
SN74LS166A . . . D OR N PACKAGE
(TOP VIEW)

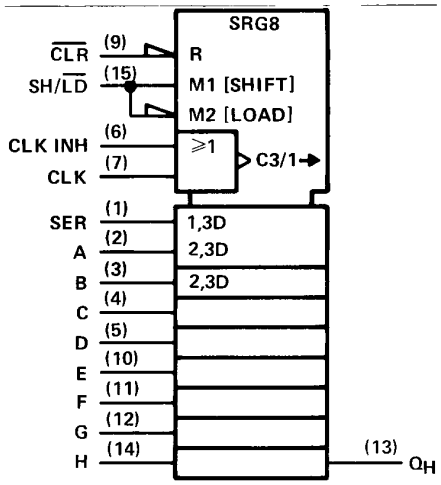


SN54LS166A . . . FK PACKAGE
(TOP VIEW)



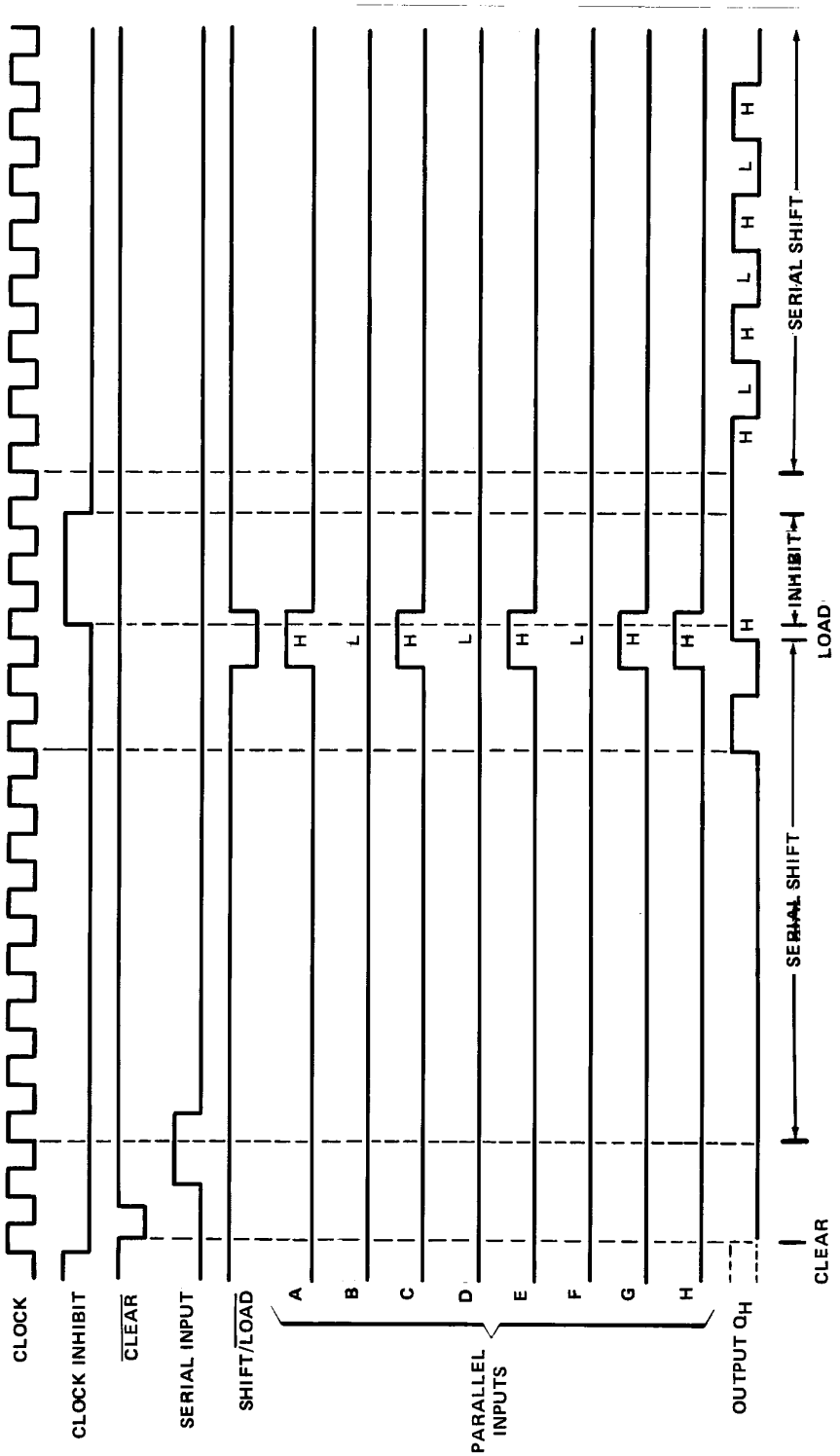
NC – No internal connection

logic symbol†



†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, N, and W packages.

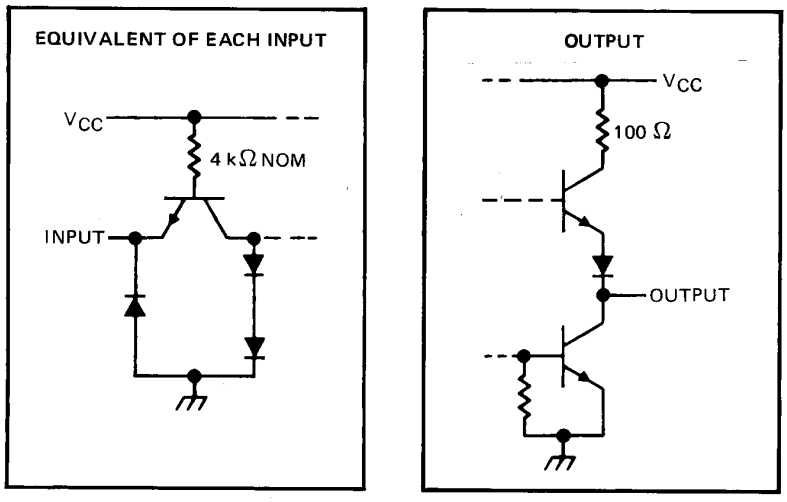
typical clear, shift, load, inhibit, and shift sequences



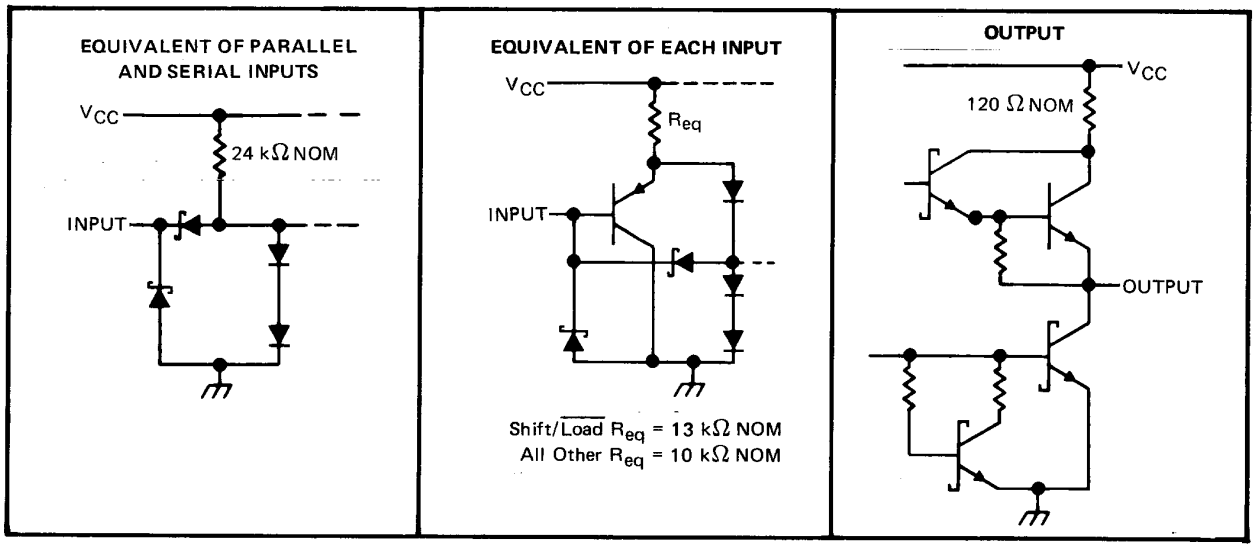
TEXAS INSTRUMENTS
POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

schematics of inputs and outputs

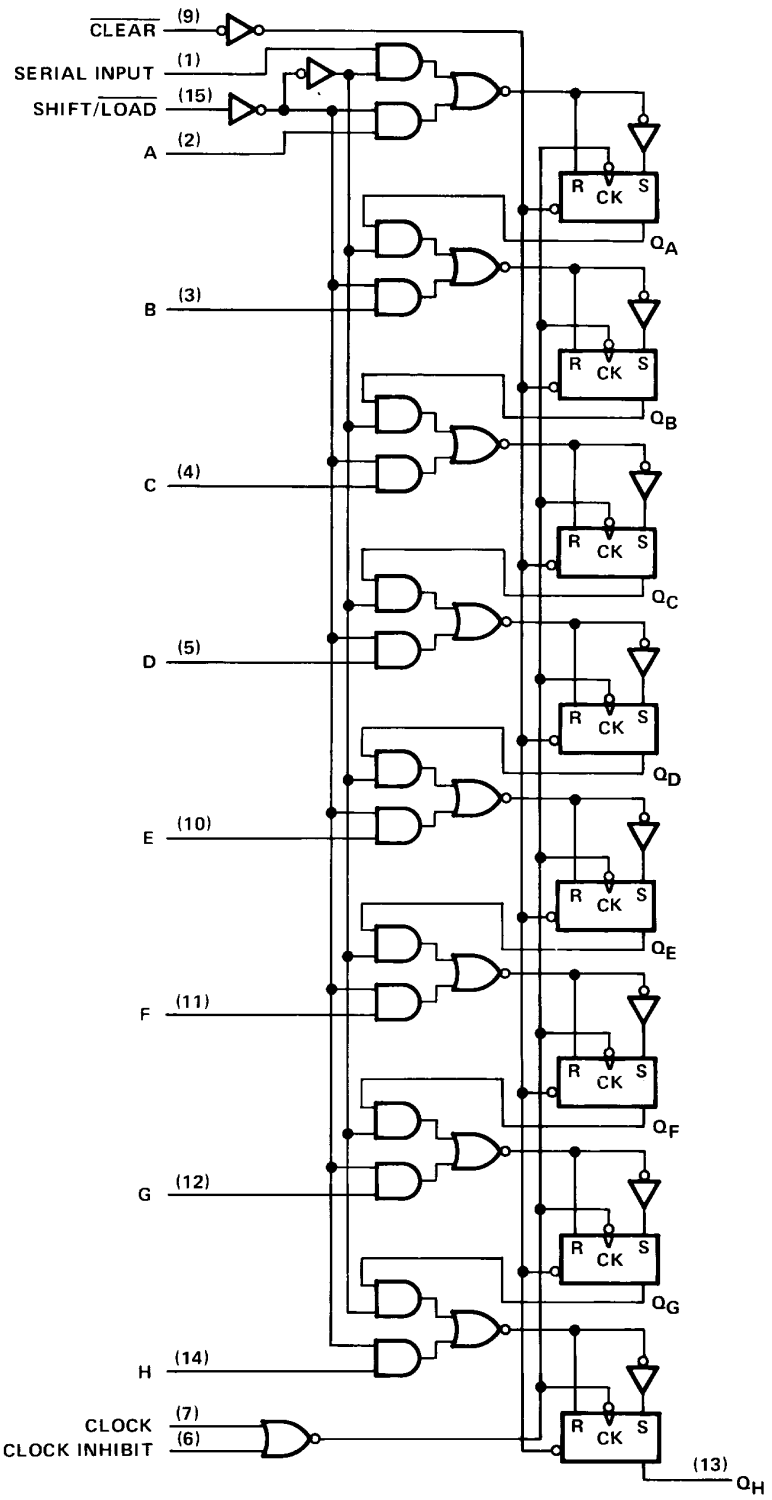
'166



'LS166A



logic diagram (positive logic)



Pin numbers shown are for D, J, N, and W packages.

TEXAS INSTRUMENTS
POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 5.5 V
Operating free-air temperature range: SN54166 (see Note 2) . . . . . −55°C to 125°C
SN74166 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

recommended operating conditions

	SN54166			SN74166			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, I_{OH}			−800			−800	μA
Low-level output current, I_{OL}			16			16	mA
Clock frequency, f_{clock}	0		25	0		25	MHz
Width of clock or clear pulse, t_w (see Figure 1)	20			20			ns
Mode-control setup time, t_{su}	30			30			ns
Data setup time, t_{su} (see Figure 1)	20			20			ns
Hold time at any input, t_h (see Figure 1)	0			0			ns
Operating free-air temperature, T_A (see Note 2)	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	SN54166			SN74166			UNIT
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
V_{IK}	Input clamp voltage	V_{CC} = MIN, I_I = −12 mA			−1.5			−1.5	V
V_{OH}	High-level output voltage	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OH} = −800 μA	2.4	3.4		2.4	3.4		V
V_{OL}	Low-level output voltage	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I_I	Input current at maximum input voltage	V_{CC} = MAX, V_I = 5.5 V			1			1	mA
I_{IH}	High-level input current	V_{CC} = MAX, V_I = 2.4 V			40			40	μA
I_{IL}	Low-level input current	V_{CC} = MAX, V_I = 0.4 V			−1.6			−1.6	mA
I_{OS}	Short-circuit output current§	V_{CC} = MAX	−20		−57	−18		−57	mA
I_{CC}	Supply current	V_{CC} = MAX, See Note 3		90	127		90	127	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡All typical values are at V_{CC} = 5 V, T_A = 25°C.
§Not more than one output should be shorted at a time.

NOTES: 1. Voltage values are with respect to network ground terminal.
2. An SN54166 in the W package operating at free-air temperatures above 113°C requires a heat-sink that provides a thermal resistance from case to free air, $R_{\theta CA}$, of not more than 48°C/W.
3. With all outputs open, 4.5 V applied to the serial input, all other inputs except the clock grounded, I_{CC} is measured after a momentary ground, then 4.5 V, is applied to the clock.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}	Maximum clock frequency	C_L = 15 pF, R_L = 400 Ω, See Figure 1	25	35		MHz
t_{PHL}	Propagation delay time, high-to-low-level output from clear			23	35	ns
t_{PHL}	Propagation delay time, high-to-low-level output from clock			20	30	ns
t_{PLH}	Propagation delay time, low-to-high-level output from clock			17	26	ns

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 7 V
Operating free-air temperature range: SN54LS166A . . . . . −55°C to 125°C
SN74LS166A . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN54LS166A			SN74LS166A			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
I_{OH}	High-level output current			−0.4			−0.4	mA
I_{OL}	Low-level output current			4			8	mA
f_{clock}	Clock frequency	0		25	0		25	MHz
t_w	Width of clear pulse (See Figure 1)	20			20			ns
t_w	Width of clock pulse (See Figure 1)	25			25			
t_{su}	Mode-control setup time	30			30			ns
t_{su}	Data setup time (See Figure 1)	20			20			ns
t_h	Hold time at any input (See Figure 1 and Note 4)	0			0			ns
T_A	Operating free air temperature	−55		125	0		70	°C

NOTE 4: The hold time limit of 0 ns applies only if the rise time is less than or equal to 10 ns.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†		SN54LS166A			SN74LS166A			UNIT
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}	V_{CC} = MIN, I_I = −18 mA				−1.5			−1.5	V
V_{OH}	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = MAX, I_{OH} = −0.4 mA		2.5	3.4		2.7	3.4		V
V_{OL}	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = MAX	I_{OL} = 4 mA		0.25	0.4		0.25	0.4	V
		I_{OL} = 8 mA					0.35	0.5	
I_I	V_{CC} = MAX, V_I = 7 V				0.1			0.1	mA
I_{IH}	V_{CC} = MAX, V_I = 2.7 V				20			20	μA
I_{IL}	V_{CC} = MAX, V_I = 0.4 V				−0.4			−0.4	mA
I_{OS}§	V_{CC} = MAX		−20		−100	−20		−100	mA
I_{CC}	V_{CC} = MAX, See Note 5			20	32		20	32	mA

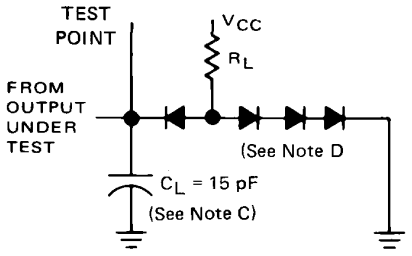
†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡All typical values are at V_{CC} = 5 V, T_A = 25°C.
§Not more than one output should be shorted at a time, and duration for short-circuit should not exceed one second.
NOTE 5: With all outputs open, 4.5 V applied to the serial input and all other inputs except the clock grounded, I_{CC} is measured after a momentary ground, than 4.5 V, is applied to clock.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}	Maximum clock frequency	C_L = 15 pF, R_L = 2 kΩ, See Figure 1	25	35		MHz
t_{PHL}	Propagation delay time, high-to-low-level output from clear			19	30	ns
t_{PHL}	Propagation delay time, high-to-low-level output from clock		7	14	25	ns
t_{PLH}	Propagation delay time, low-to-high-level output from clock		5	11	20	ns

TEXAS INSTRUMENTS
POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

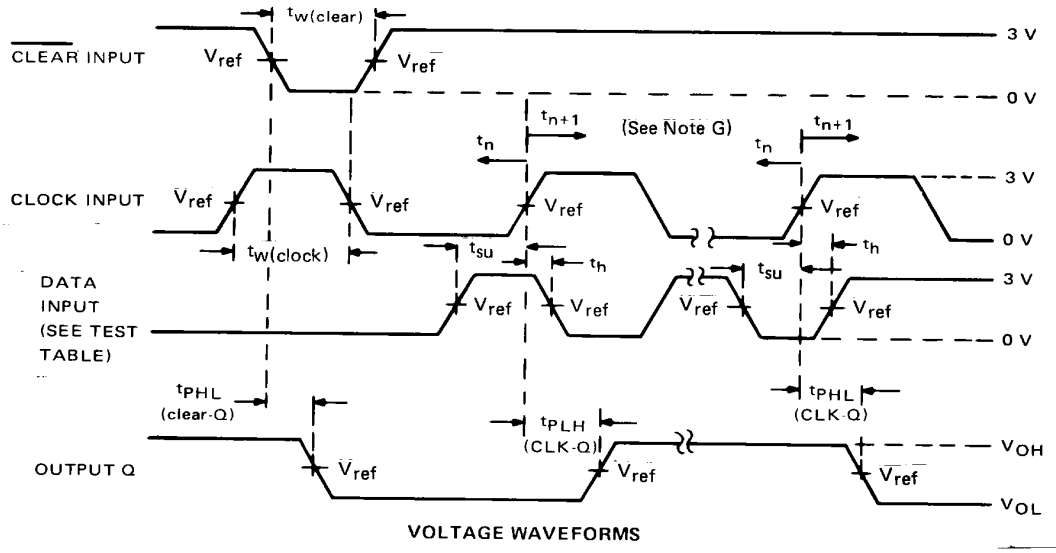
PARAMETER MEASUREMENT INFORMATION



LOAD FOR OUTPUT UNDER TEST

TEST TABLE FOR SYNCHRONOUS INPUTS

DATA INPUT FOR TEST	SHIFT/$\overline{\text{LOAD}}$	OUTPUT TESTED (SEE NOTE F)
H	0 V	Q_H at t_{n+1}
Serial Input	4.5 V	Q_H at t_{n+8}



VOLTAGE WAVEFORMS

NOTE: A. All pulse generators have the following characteristics: $Z_{out} \approx 50\Omega$; for '166, $t_r \leq 7$ ns and $t_f \leq 7$ ns; for 'LS166A, $t_r \leq 15$ ns and $t_f \leq 6$ ns.

B. The clock pulse has the following characteristics: $t_{w(clock)} \leq 20$ ns and PRR = 1 MHz. The clear pulse has the following characteristics: $t_{w(clear)} \leq 20$ ns and $t_{hold} = 0$ ns. When testing f_{max}, vary the clock PRR.

C. C_L includes probe and jig capacitance.

D. All diodes are 1N3064, 1N916, or equivalent.

E. A clear pulse is applied prior to each test.

F. Propagation delay times (t_{PLH} and t_{PHL}) are measured at t_{n+1}. Proper shifting of data is verified at t_{n+8} with a functional test.

G. t_n = bit time before clocking transition
t_{n+1} = bit time after one clocking transition
t_{n+8} = bit time after eight clocking transitions

H. For '166 V_{ref} = 1.5 V; for 'LS166A V_{ref} = 1.3 V.

FIGURE 1

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.